

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known	
		Application Number	10/780,143
		Filing Date	FEBRUARY 18, 2004
		First Named Inventor	Alexander L. Barr et al.
		Group Art Unit	2823
		Examiner Name	W. DAVID COLEMAN
Sheet	1	of	1
		Attorney Docket Number	SC13265TP

U. S. PATENT DOCUMENTS					
Examiner Initials ¹	Cite No. ¹	Document Number Number - Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	US -6,429,061 B1	08-06-2002	RIM	
		US -			
		US -			
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FOREIGN PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	AB	PCT WO02/080241 A1	10-10-2002	IBM		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁷
	AC	LANGDO et al., "Preparation of Novel SiGe-Free Strained Si on Insulator Substrates," AMBERWAVE SYSTEMS CORP., SALEM, NH, 2 pgs.	
	AD	MATSUMOTO et al., "Novel SOI Wafer Engineering Using Low Stress and High Mobility CMOSFET with <100> Channel for Embedded RF/Analog Applications," IEEE, pp. 663-666 (2002).	
	AE	SAYAMA et al., "Effect of <100> Channel Direction for High Performance SCE Immune pMOSFET with Less Than 0.15µm Gate Length," IEEE, 4 pgs., (1999).	
	AF	AOKI et al., "Optimum Crystallographic Orientation of Submicrometer CMOS Devices Operated at Low Temperatures," IEEE TRANSACTIONS ON ELECTRON DEVICES, VOL. ED-34, NO. 1, JANUARY 1987, pp. 52-57.	

Examiner Signature		Date Considered	October 4, 2005
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